Notice of References Cited Application/Control No. 10/648,229 Examiner Abdou Karim Seye Applicant(s)/Patent Under Reexamination CHEN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
*	Α	US-2003/0074592	04-2003	Hasegawa, Toshitaka	713/324	
*	В	US-2002/0037713	03-2002	Kato, Akira	455/414	
*	O	US-2003/0054821	03-2003	Kita et al.	455/435	
*	D	US-2004/0259642	12-2004	Tanaka et al.	463/042	
	Е	US-				
	F	US-				
	G	US-				
	Н	US-				
	ı	US-				
	J	US-				
	К	US-				
	L	US-				
	М	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.